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The application domain of the published articles is electronic circuits and systems used for computing and communications. Broadly, the topics include hardware testing, verification, design for testability, reliability and security.

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Journal Website

www.springer.com/10836

Electronic edition: link.springer.com/journal/10836

For the actual version of record please always check the online version of the publication.

Subscription Information

Journal of Electronic Testing: Theory and Applications is published 6 times a year. Volume 38 (6 issues) will be published in 2022.

ISSN: 0923-8174 print

ISSN: 1573-0727 electronic

For information on subscription rates please contact Springer Nature Customer Service Center: customerservice@springernature.com

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